

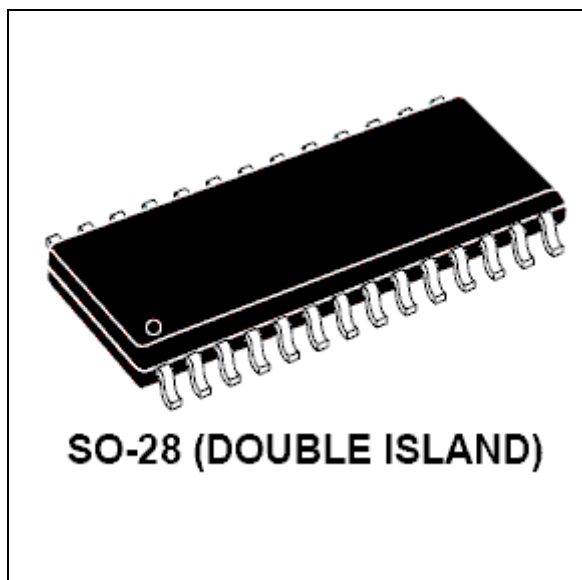
Double channel high side solid state relay

Features

Type	$R_{DS(on)}$	I_{OUT}	V_{CC}
VND920P	16 mΩ	35 A	36 V ⁽¹⁾

1. Per channel with all the output pins connected to the PCB.

- CMOS compatible input
- Proportional load current sense
- Shorted load protection
- Undervoltage and overvoltage shutdown
- Overvoltage clamp
- Thermal shutdown
- Current limitation
- Protection against loss of ground and loss of V_{CC}
- Very low standby power dissipation
- Reverse battery protection ^(a)



Description

The VND920P is a double chip device made by using STMicroelectronics VIPower M0-3 Technology, intended for driving any kind of load with one side connected to ground. Active V_{CC} pin voltage clamp protects the device against low energy spikes (see ISO7637 transient compatibility table). Active current limitation combined with thermal shutdown and automatic restart protect the device against overload. Built-in analog current sense output delivers a current proportional to the load current. Device automatically turns off in case of ground pin disconnection

a. See [Figure 8: Application schematic on page 16](#)

Table 1. Device summary

Package	Tube	Tube (lead free)	Tape and reel	Tape and reel (lead free)
SO-28	VND920P	VND920P-E	VND920P13TR	VND920PTR-E

Contents

1	Block diagram	5
2	Pin description	6
3	Electrical specification	7
3.1	Absolute maximum rating	7
3.2	Thermal data	8
3.3	Electrical characteristics	8
3.4	Truth table	12
3.5	Electrical transient requirements	12
3.5.1	GND protection network against reverse battery	15
3.5.2	Load dump protection	16
3.5.3	μC I/Os protection	16
4	SO-28 double island thermal data	20
5	Package information	23
6	Revision history	25

List of tables

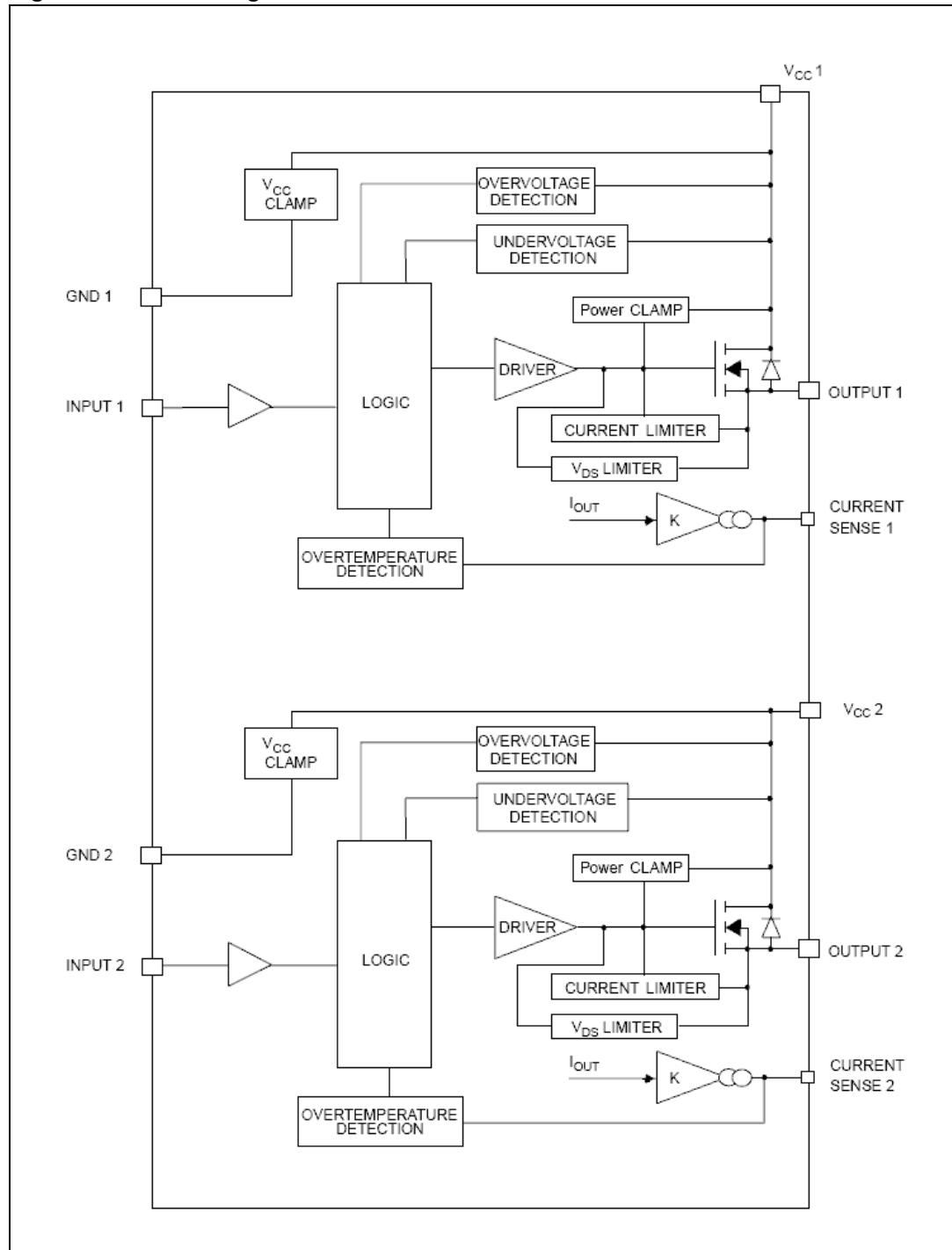
Table 1.	Device summary	1
Table 2.	Absolute maximum rating (per each channel)	7
Table 3.	Thermal data (per island)	8
Table 4.	Electrical characteristics	8
Table 5.	Truth table (per each channel)	12
Table 6.	Electrical transient requirements (part 1/3)	12
Table 7.	Electrical transient requirements (part 2/3)	12
Table 8.	Electrical transient requirements (part 3/3)	13
Table 9.	Thermal calculation according to the PCB heatsink area	20
Table 10.	Thermal parameter	22
Table 11.	Document revision history	25

List of figures

Figure 1.	Block diagram	5
Figure 2.	Connection diagram (top view)	6
Figure 3.	Current and voltage conventions	7
Figure 4.	I_{OUT}/I_{SENSE} versus I_{OUT}	11
Figure 5.	Switching characteristics (resistive load $R_L=1.3\ \Omega$)	12
Figure 6.	Switching time waveforms	12
Figure 7.	Waveforms	15
Figure 8.	Application schematic	16
Figure 9.	Off-state output current	18
Figure 10.	High level input current	18
Figure 11.	Input clamp voltage	18
Figure 12.	Input high level	18
Figure 13.	Input low level	18
Figure 14.	Input hysteresis voltage	18
Figure 15.	Overvoltage shutdown	19
Figure 16.	I_{LIM} vs T_{case}	19
Figure 17.	Turn-on voltage slope (part 1/2)	19
Figure 18.	Turn-off voltage slope (part 2/2)	19
Figure 19.	On-state resistance vs T_{case}	19
Figure 20.	On-state resistance vs V_{CC}	19
Figure 21.	Maximum turn-off current versus load inductance	20
Figure 22.	Demagnetization	20
Figure 23.	SO-28 double island PC board	21
Figure 24.	$R_{thj-amb}$ vs PCB copper area in open box free air condition	21
Figure 25.	SO-28 thermal impedance junction ambient single pulse	22
Figure 26.	Thermal fitting model of a two channels HSD in SO-28	22
Figure 27.	SO-28 mechanical data	24
Figure 28.	SO-28 tube shipment (no suffix)	25
Figure 29.	Tape and reel shipment (suffix "13TR")	25

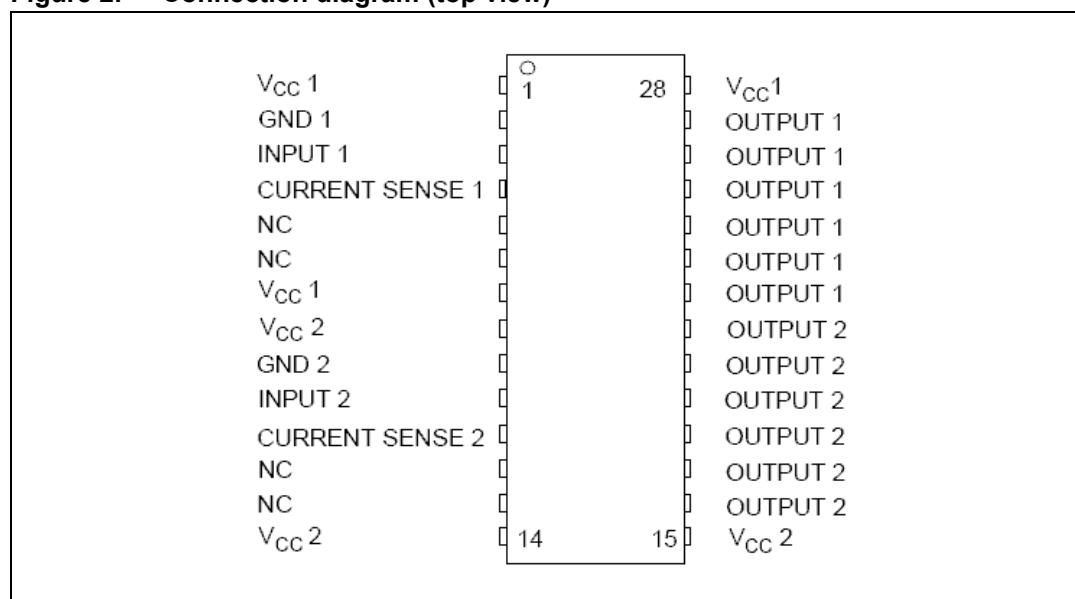
1 Block diagram

Figure 1. Block diagram



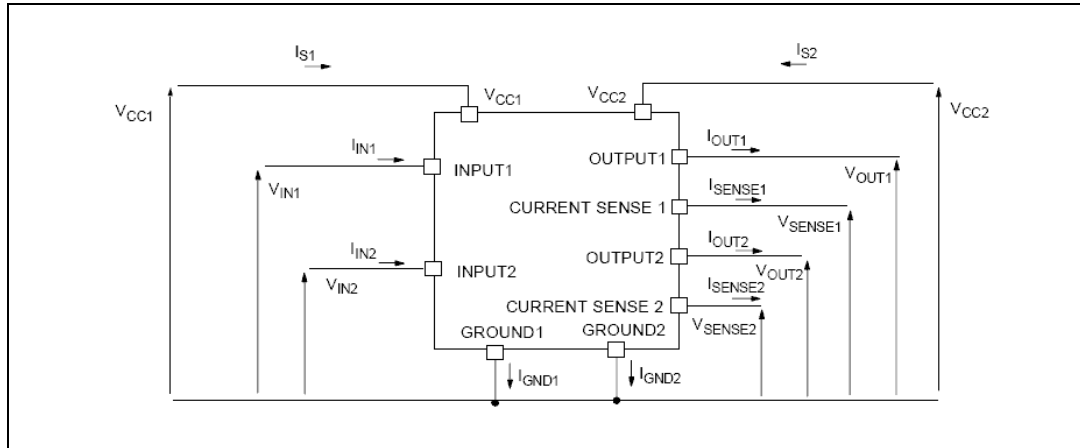
2 Pin description

Figure 2. Connection diagram (top view)



3 Electrical specification

Figure 3. Current and voltage conventions



3.1 Absolute maximum rating

Table 2. Absolute maximum rating (per each channel)

Symbol	Parameter	Value	Unit
V_{CC}	DC supply voltage	41	V
$-V_{CC}$	Reverse DC supply voltage	-0.3	V
$-I_{GND}$	DC reverse ground pin current	-200	mA
I_{OUT}	DC output current	Internally limited	A
$-I_{OUT}$	Reverse DC output current	-21	A
I_{IN}	DC input current	+/-10	mA
V_{CSENSE}	Current sense maximum voltage	-3 +15	V V
V_{ESD}	Electrostatic discharge (human body model: $R=1.5\text{ K}\Omega$; $C=100\text{ pF}$) - Input - Current sense - Output - V_{CC}	4000 2000 5000 5000	V V V V
E_{MAX}	Maximum switching energy ($L=0.25\text{ mH}$; $R_L=0\text{ }\Omega$; $V_{bat}=13.5\text{ V}$; $T_{jstart}=150\text{ }^\circ\text{C}$; $I_L=45\text{ A}$)	355	mJ
P_{tot}	Power dissipation $T_j \leq 25\text{ }^\circ\text{C}$	6.25 ⁽¹⁾	W
T_j	Junction operating temperature	Internally limited	$^\circ\text{C}$
T_c	Case operating temperature	- 40 to 150	$^\circ\text{C}$
T_{STG}	Storage temperature	- 55 to 150	$^\circ\text{C}$

1. Per Island

3.2 Thermal data

Table 3. Thermal data (per island)

Symbol	Parameter	Value	Unit
$R_{thj-lead}$	Thermal resistance junction-lead	20	°C/W
$R_{thj-amb}$	Thermal resistance junction-ambient (one chip on)	55 ⁽¹⁾	°C/W
$R_{thj-amb}$	Thermal resistance junction-ambient (two chip on)	42 ⁽¹⁾	°C/W

1. When mounted on a standard single-sided FR-4 board with 1 cm² of Cu (at least 35 µm thick) connected to all V_{CC} pins. Horizontal mounting and no artificial air flow.

3.3 Electrical characteristics

8 V < V_{CC} < 36 V; -40 °C < T_j < 150 °C unless otherwise specified.

Per island.

Table 4. Electrical characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
Power						
V _{CC}	Operating supply voltage		5.5	13	36	V
V _{USD}	Undervoltage shutdown		3	4	5.5	V
V _{OV}	Overvoltage shutdown		36			V
R _{ON}	On-state resistance	I _{OUT} =10 A; T _j =25 °C I _{OUT} =10 A I _{OUT} =3 A; V _{CC} =6 V			16 32 55	mΩ mΩ mΩ
V _{CLAMP}	Clamp voltage	I _{CC} =20 mA ⁽¹⁾	41	48	55	V
I _S	Supply current	Off-state; V _{CC} =13 V; V _{IN} =V _{OUT} =0 V Off-state; V _{CC} =13 V; V _{IN} =V _{OUT} =0 V; T _j =25 °C On-state; V _{CC} =13 V; V _{IN} =5 V; I _{OUT} =0 A; R _{SENSE} =3.9 KΩ		10 10	25 20 5	µA µA mA
I _{L(off1)}	Off-state output current	V _{IN} =V _{OUT} =0 V	0		50	µA
I _{L(off2)}	Off-state output current	V _{IN} =0 V; V _{OUT} =3.5 V	-75		0	µA
I _{L(off3)}	Off-state output current	V _{IN} =V _{OUT} =0 V; V _{CC} =13 V; T _j =125 °C			5	µA
I _{L(off4)}	Off-state output current	V _{IN} =V _{OUT} =0 V; V _{CC} =13 V; T _j =25 °C			3	µA
Switching (V_{CC}=13 V)						
t _{d(on)}	Turn-on delay time	R _L = 1.3 Ω (see Figure 5)		50		µs
t _{d(off)}	Turn-off delay time	R _L = 1.3 Ω (see Figure 5)		50		µs
dV _{OUT} /dt _(on)	Turn-on voltage slope	R _L = 1.3 Ω (see Figure 5)		See relative diagram		V/µs

Table 4. Electrical characteristics (continued)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$dV_{OUT}/dt_{(off)}$	Turn-off voltage slope	$R_L = 1.3 \Omega$ (see Figure 5)		See relative diagram		V/ μ s
Logic input						
V_{IL}	Input low level				1.25	V
I_{IL}	Low level input current	$V_{IN} = 1.25 \text{ V}$	1			μ A
V_{IH}	Input high level		3.25			V
I_{IH}	High level input current	$V_{IN} = 3.25 \text{ V}$			10	μ A
$V_{I(hyst)}$	Input hysteresis voltage		0.5			V
V_{ICL}	Input clamp voltage	$I_{IN}=1 \text{ mA}$ $I_{IN}=-1 \text{ mA}$	6	6.8 -0.7	8	V V
Current sense ($9 \text{ V} \leq V_{CC} \leq 16 \text{ V}$) (see Figure 4)						
K_1	I_{OUT}/I_{SENSE}	$I_{OUT}=1 \text{ A}$; $V_{SENSE}=0.5 \text{ V}$; $T_j = -40 \text{ }^\circ\text{C} \dots 150 \text{ }^\circ\text{C}$	3300	4400	6000	
dK_1/K_1	Current sense ratio drift	$I_{OUT}=1 \text{ A}$; $V_{SENSE}=0.5 \text{ V}$; $T_j = -40 \text{ }^\circ\text{C} \dots 150 \text{ }^\circ\text{C}$	-10		+10	%
K_2	I_{OUT}/I_{SENSE}	$I_{OUT}=10 \text{ A}$; $V_{SENSE}=4 \text{ V}$; $T_j = -40 \text{ }^\circ\text{C}$ $T_j = 25 \text{ }^\circ\text{C} \dots 150 \text{ }^\circ\text{C}$	4200 4400	4900 4900	6000 5750	
dK_2/K_2	Current sense ratio drift	$I_{OUT}=10 \text{ A}$; $V_{SENSE}=4 \text{ V}$; $T_j = -40 \text{ }^\circ\text{C} \dots 150 \text{ }^\circ\text{C}$	-8		-8	%
K_3	I_{OUT}/I_{SENSE}	$I_{OUT}=30 \text{ A}$; $V_{SENSE}=4 \text{ V}$; $T_j = -40 \text{ }^\circ\text{C}$ $T_j = 25 \text{ }^\circ\text{C} \dots 150 \text{ }^\circ\text{C}$	4200 4400	4900 4900	5500 5250	
dK_3/K_3	Current sense ratio drift	$I_{OUT}=30 \text{ A}$; $V_{SENSE}=4 \text{ V}$; $T_j = -40 \text{ }^\circ\text{C} \dots 150 \text{ }^\circ\text{C}$	-6		+6	%
I_{SENSE0}	Analog sense leakage current	$V_{CC}=6 \dots 16 \text{ V}$; $I_{OUT}=0 \text{ A}$; $V_{SENSE}=0 \text{ V}$; $T_j = -40 \text{ }^\circ\text{C} \dots 150 \text{ }^\circ\text{C}$	0		10	μ A
V_{SENSE}	Max analog sense output voltage	$V_{CC}=5.5 \text{ V}$; $I_{OUT}=5 \text{ A}$; $R_{SENSE}=10 \text{ K}\Omega$ $V_{CC}>8 \text{ V}$; $I_{OUT}=10 \text{ A}$; $R_{SENSE}=10 \text{ K}\Omega$	2 4			V V
V_{SENSEH}	Sense voltage in over temperature conditions	$V_{CC}=13 \text{ V}$; $R_{SENSE}=3.9 \text{ K}\Omega$		5.5		V
$R_{VSENSEH}$	Analog sense output impedance in over temperature condition	$V_{CC}=13 \text{ V}$; $T_j > T_{TSD}$; All channel open		400		Ω
t_{DSENSE}	Current sense delay response	to 90 % $I_{SENSE}^{(2)}$			500	μ s
Protection						
T_{TSD}	Shutdown temperature		150	175	200	$^\circ\text{C}$

Table 4. Electrical characteristics (continued)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
T_R	Reset temperature		135			°C
T_{hyst}	Thermal hysteresis		7	15		°C
I_{lim}	DC short circuit current	$V_{CC}=13\text{ V}$ $5\text{ V} < V_{CC} < 36\text{ V}$	30	45	75 75	A A
V_{demag}	Turn-off output clamp voltage	$I_{OUT}=2\text{ A}$; $V_{IN}=0\text{ V}$; $L=6\text{ mH}$	$V_{CC}-41$	$V_{CC}-48$	$V_{CC}-55$	V
V_{ON}	Output voltage drop limitation	$I_{OUT}=1\text{ A}$; $T_j=-40\text{ °C}...+150\text{ °C}$		50		mV

1. V_{clamp} and V_{OV} are correlated. Typical difference is 5 V.

2. Current sense signal delay after positive input slope

Note: Sense pin doesn't have to be left floating.

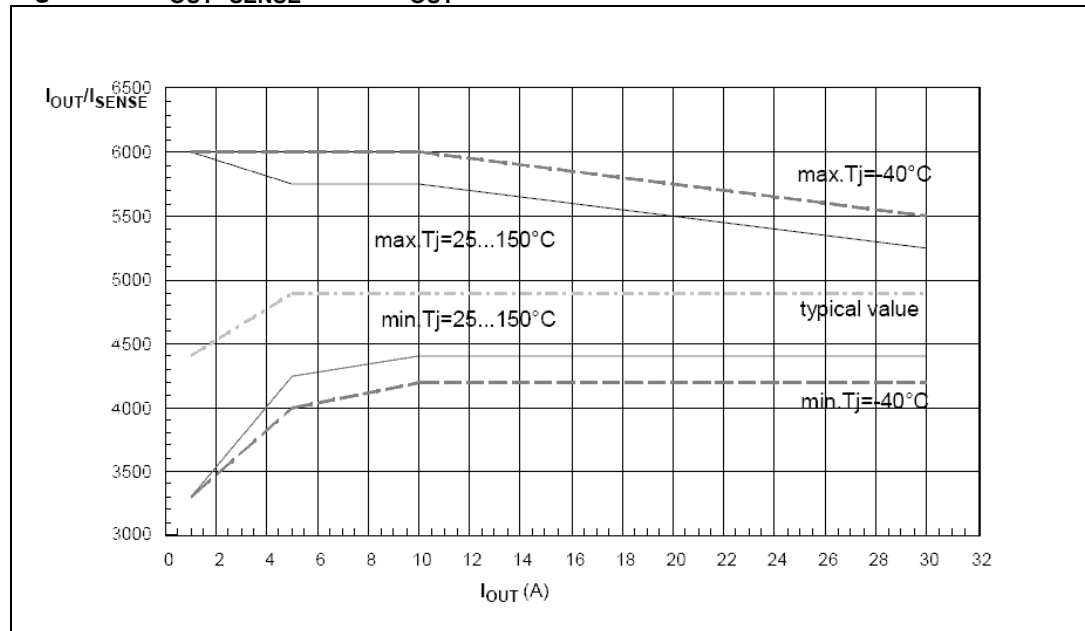
Figure 4. I_{OUT}/I_{SENSE} versus I_{OUT} 

Figure 5. Switching characteristics (resistive load $R_L=1.3\ \Omega$)

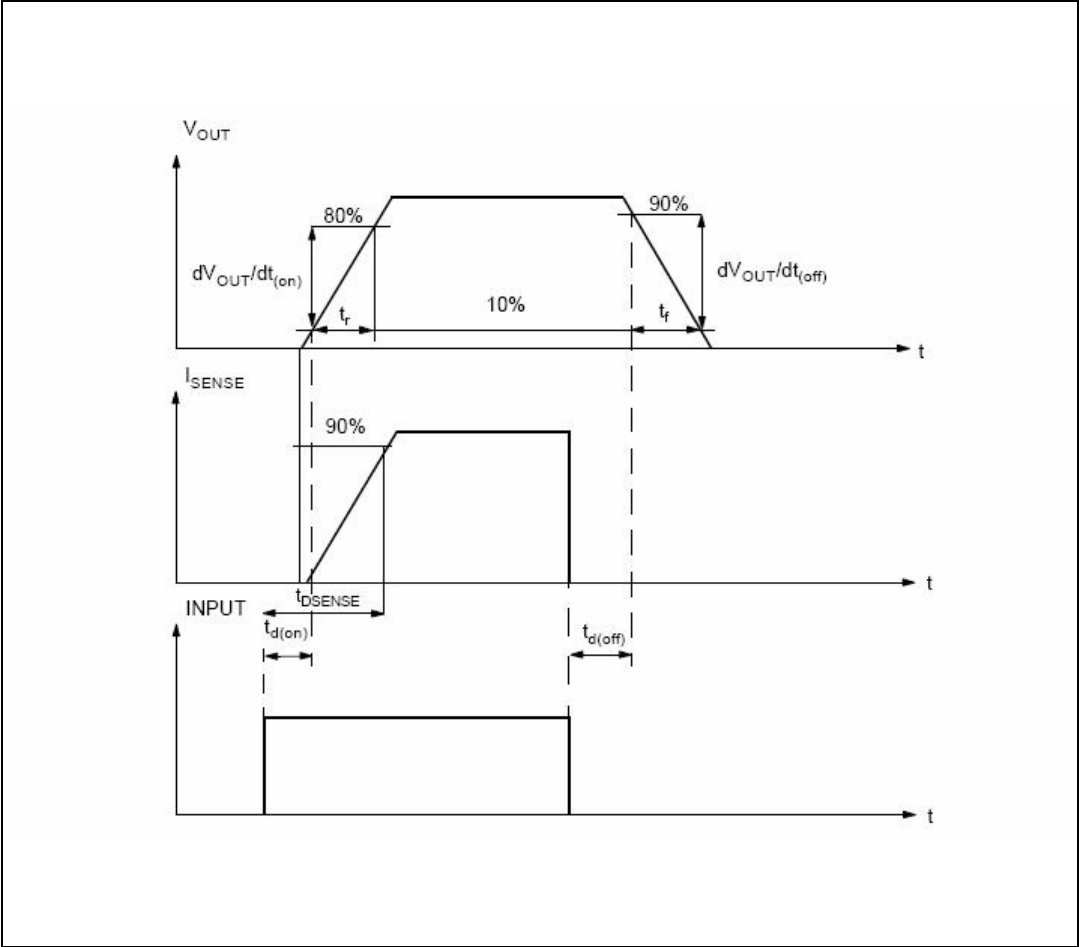
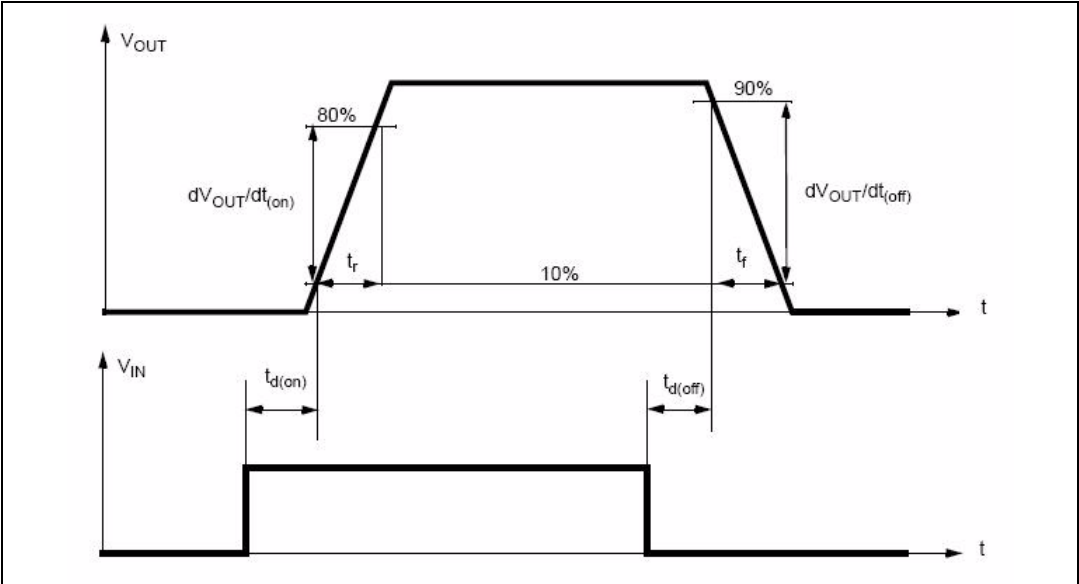


Figure 6. Switching time waveforms



3.4 Truth table

Table 5. Truth table (per each channel)

Condition	Input	Output	Current sense
Normal operation	L	L	0
	H	H	Nominal
Over temperature	L	L	0
	H	L	V_{SENSEH}
Undervoltage	L	L	0
	H	L	0
Overvoltage	L	L	0
	H	L	0
Short circuit to GND	L	L	0
	H	L	$(T_j < T_{TSD})$ 0
	H	L	$(T_j > T_{TSD}) V_{SENSEH}$
Short circuit to V_{CC}	L	H	0
	H	H	< Nominal
Negative output voltage clamp	L	L	0

3.5 Electrical transient requirements

Table 6. Electrical transient requirements (part 1/3)

ISO T/R 7637/1 test pulse	Test levels				
	I	II	III	IV	Delays and impedance
1	-25 V	-50 V	-75 V	-100 V	2 ms 10 Ω
2	+25 V	+50 V	+75 V	+100 V	0.2 ms 10 Ω
3a	-25 V	-50 V	-100 V	-150 V	0.1 μ s 50 Ω
3b	+25 V	+50 V	+75 V	+100 V	0.1 μ s 50 Ω
4	-4 V	-5 V	-6 V	-7 V	100 ms, 0.01 Ω
5	+26.5 V	+46.5 V	+66.5 V	+86.5 V	400 ms, 2 Ω

Table 7. Electrical transient requirements (part 2/3)

ISO T/R 7637/1 test pulse	Test levels results			
	I	II	III	IV
1	C	C	C	C
2	C	C	C	C
3a	C	C	C	C

Table 7. Electrical transient requirements (part 2/3) (continued)

ISO T/R 7637/1 test pulse	Test levels results			
	I	II	III	IV
3b	C	C	C	C
4	C	C	C	C
5	C	E	E	E

Table 8. Electrical transient requirements (part 3/3)

Class	Contents
C	All functions of the device are performed as designed after exposure to disturbance.
E	One or more functions of the device is not performed as designed after exposure to disturbance and cannot be returned to proper operation without replacing the device.

Figure 7. Waveforms

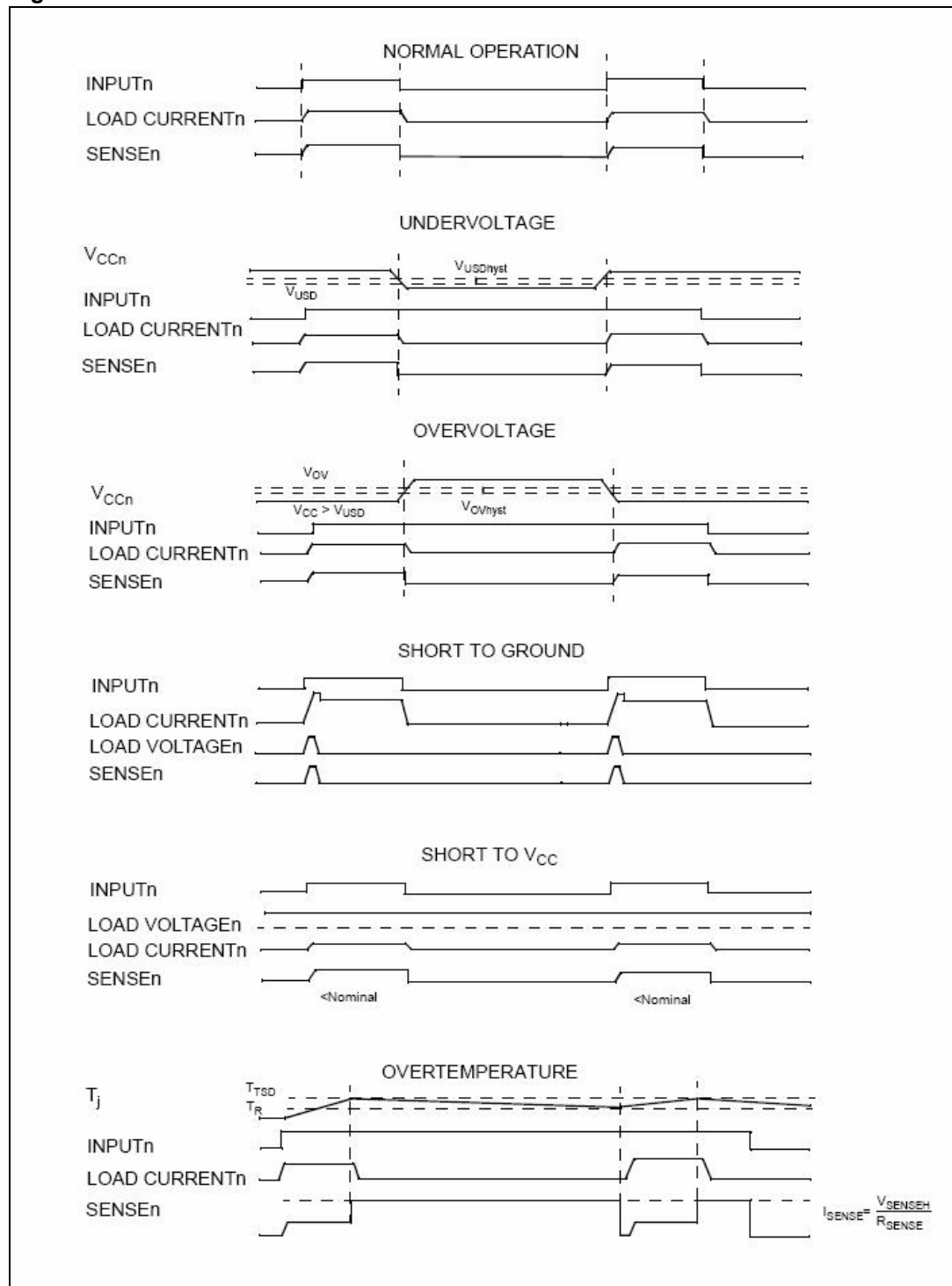
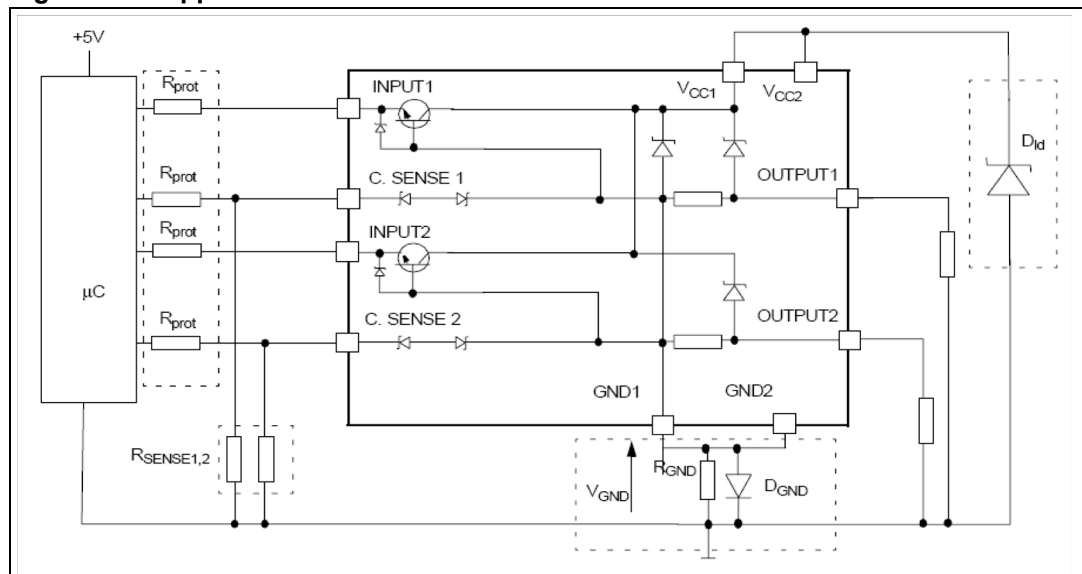


Figure 8. Application schematic



3.5.1 GND protection network against reverse battery

Solution 1: Resistor in the ground line (R_{GND} only). This can be used with any type of load.

The following is an indication on how to dimension the R_{GND} resistor.

$$1) R_{GND} \leq 600 \text{ mV} / (I_{S(on)max})$$

$$2) R_{GND} \geq (-V_{CC}) / (-I_{GND})$$

where $-I_{GND}$ is the DC reverse ground pin current and can be found in the absolute maximum rating section of the device's datasheet. Power dissipation in R_{GND} (when $V_{CC} < 0$: during reverse battery situations) is:

$$P_D = (-V_{CC})^2 / R_{GND}$$

This resistor can be shared amongst several different HSD. Please note that the value of this resistor should be calculated with formula (1) where $I_{S(on)max}$ becomes the sum of the maximum on-state currents of the different devices.

Please note that if the microprocessor ground is not common with the device ground then the R_{GND} will produce a shift ($I_{S(on)max} * R_{GND}$) in the input thresholds and the status output values. This shift will vary depending on how many devices are on in the case of several high side drivers sharing the same R_{GND} .

If the calculated power dissipation leads to a large resistor or several devices have to share the same resistor then the ST suggests to utilize solution 2 (see below).

Solution 2: A diode (D_{GND}) in the ground line. A resistor ($R_{GND} = 1 \text{ k}\Omega$) should be inserted in parallel to D_{GND} if the device will be driving an inductive load.

This small signal diode can be safely shared amongst several different HSD. Also in this case, the presence of the ground network will produce a shift ($\cong 600 \text{ mV}$) in the input threshold and the status output values if the microprocessor ground is not common with the device ground. This shift will not vary if more than one HSD shares the same diode/resistor network.

Series resistor in input and status lines are also required to prevent that, during battery voltage transient, the current exceeds the absolute maximum rating.

Safest configuration for unused input and status pin is to leave them unconnected.

3.5.2 Load dump protection

D_{ld} is necessary (Voltage Transient Suppressor) if the load dump peak voltage exceeds V_{CC} max DC rating. The same applies if the device will be subject to transients on the V_{CC} line that are greater than the ones shown in the ISO T/R 7637/1 table.

3.5.3 μC I/Os protection

If a ground protection network is used and negative transients are present on the V_{CC} line, the control pins will be pulled negative. ST suggests to insert a resistor (R_{prot}) in line to prevent the μC I/Os pins to latch-up.

The value of these resistors is a compromise between the leakage current of μC and the current required by the HSD I/Os (Input levels compatibility) with the latch-up limit of μC I/Os.

$$-V_{CCpeak}/I_{latchup} \leq R_{prot} \leq (V_{OH\mu C} - V_{IH} - V_{GND}) / I_{IHmax}$$

Calculation example:

For $V_{CCpeak} = -100\text{ V}$ and $I_{latchup} \geq 20\text{ mA}$; $V_{OH\mu C} \geq 4.5\text{ V}$ $5\text{ k}\Omega \leq R_{prot} \leq 65\text{ k}\Omega$.

Recommended R_{prot} value is $10\text{ k}\Omega$.

Figure 9. Off-state output current

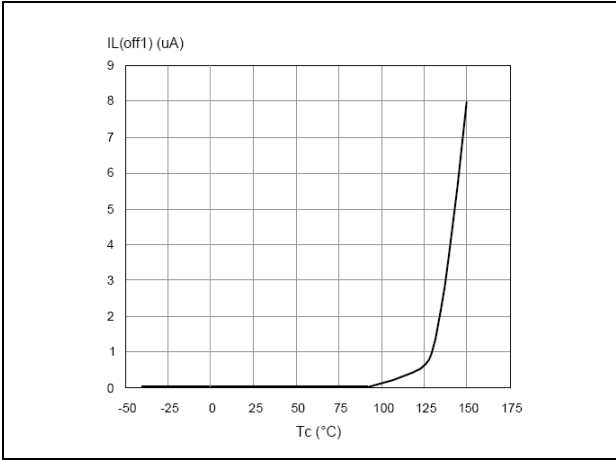


Figure 10. High level input current

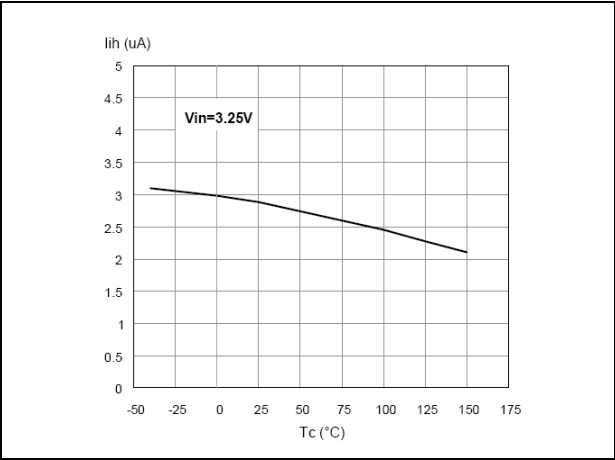


Figure 11. Input clamp voltage

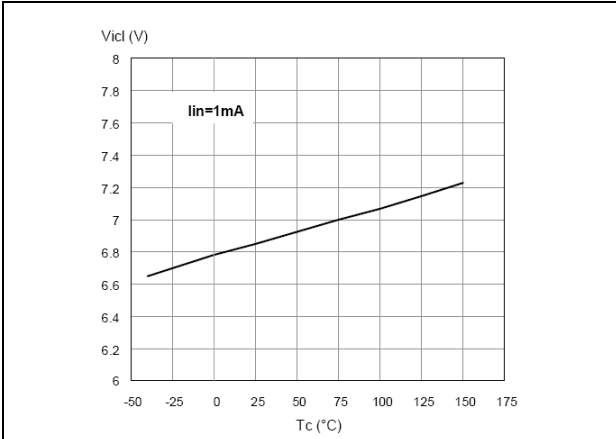


Figure 12. Input high level

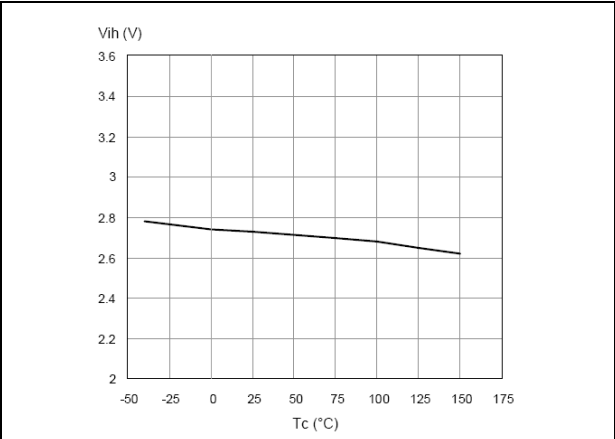


Figure 13. Input low level

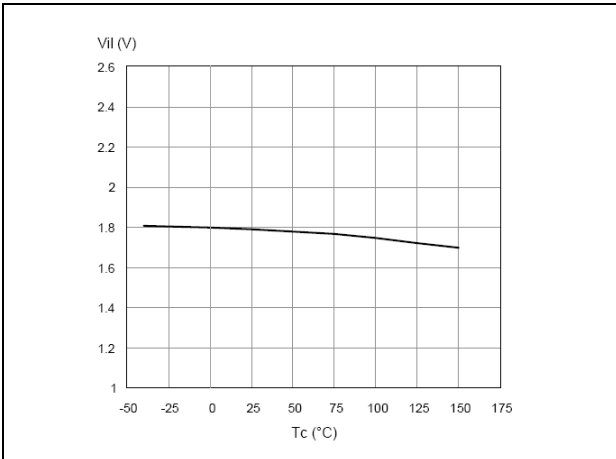


Figure 14. Input hysteresis voltage

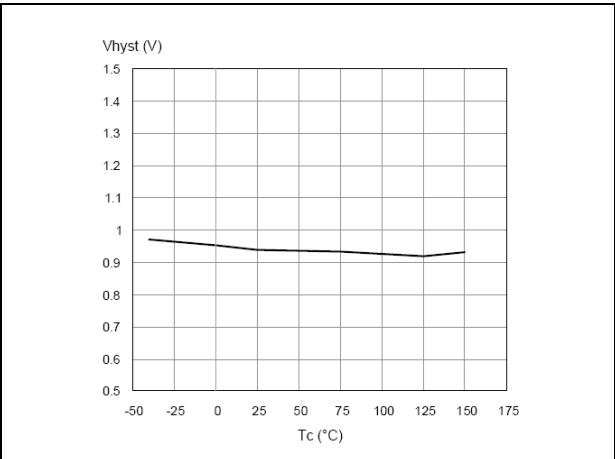


Figure 15. Overvoltage shutdown

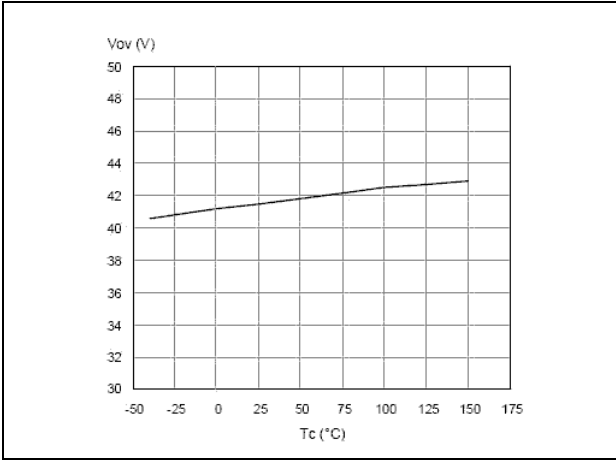


Figure 16. I_{LIM} vs T_{case}

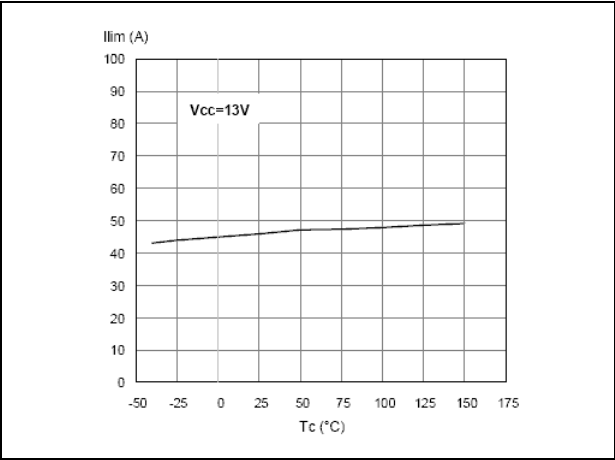


Figure 17. Turn-on voltage slope (part 1/2)

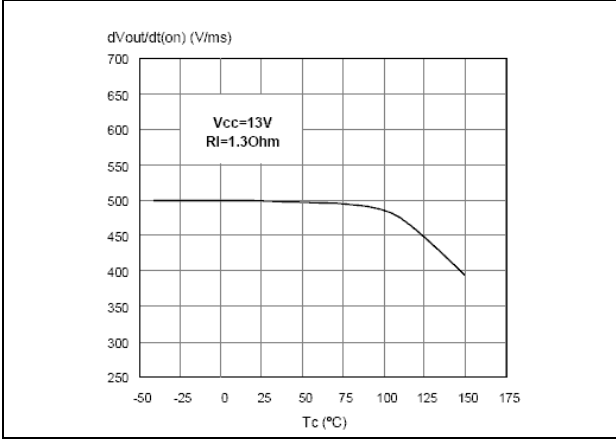


Figure 18. Turn-off voltage slope (part2/2)

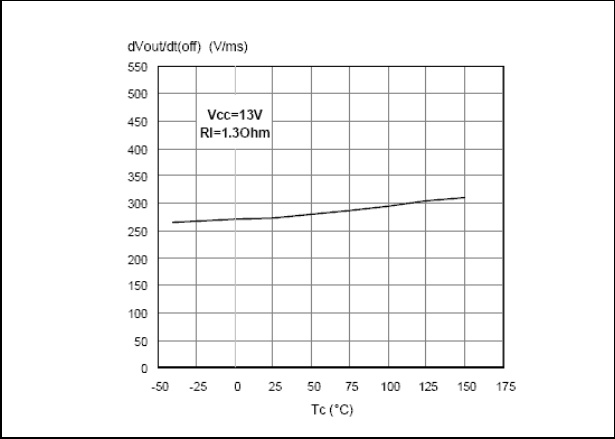


Figure 19. On-state resistance vs T_{case}

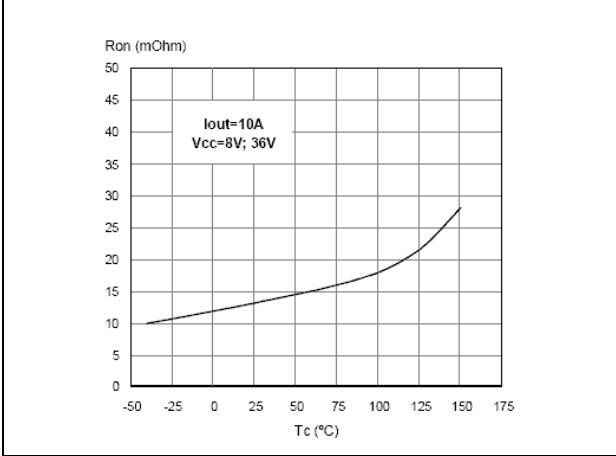


Figure 20. On-state resistance vs V_{CC}

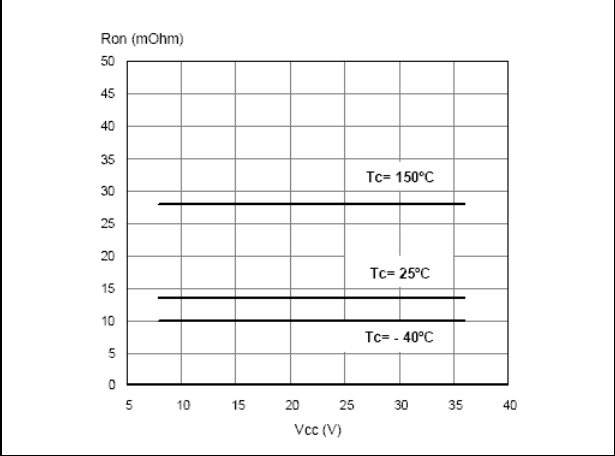
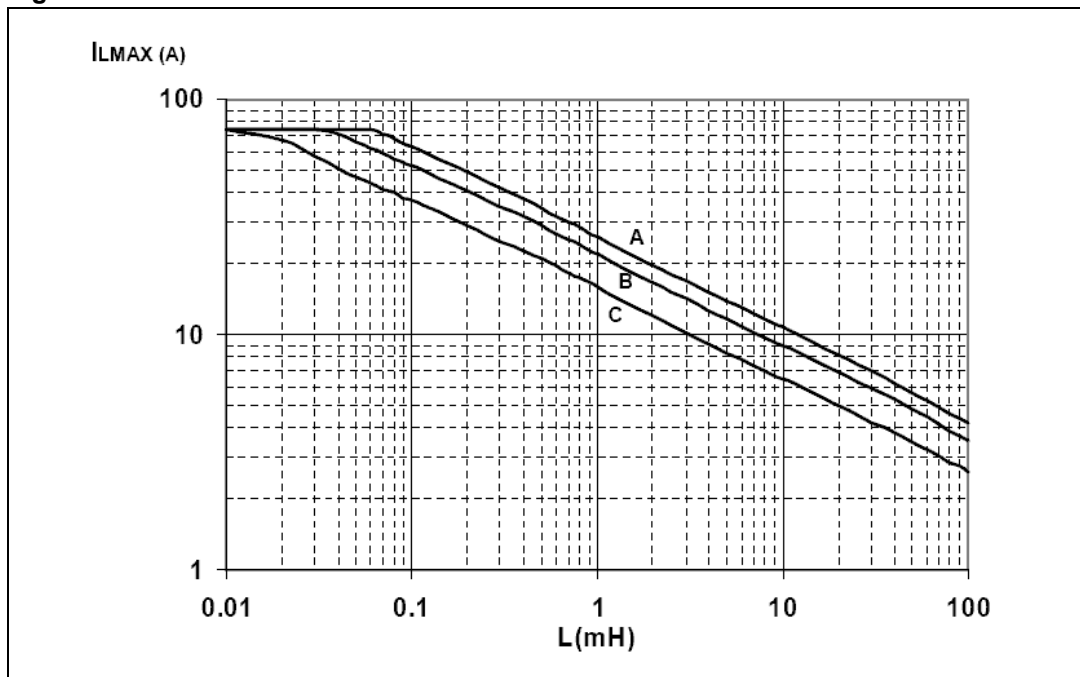


Figure 21. Maximum turn-off current versus load inductance

Legend:

A= Single pulse at $T_{jstart}=150\text{ }^{\circ}\text{C}$

B= Repetitive pulse at $T_{jstart}=100\text{ }^{\circ}\text{C}$

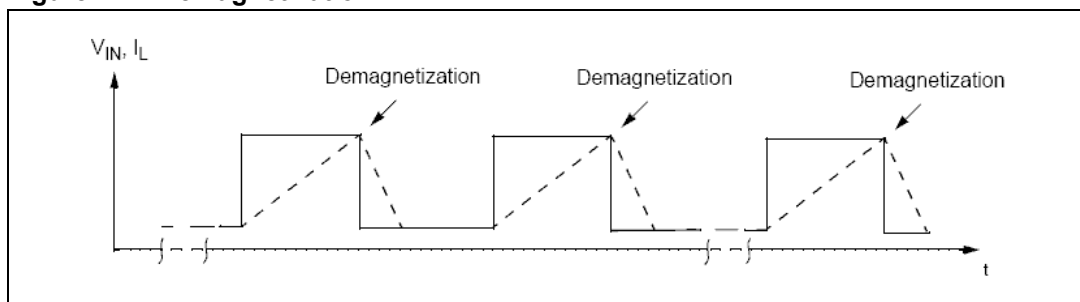
C= Repetitive pulse at $T_{jstart}=125\text{ }^{\circ}\text{C}$

Conditions:

$V_{CC}=13.5\text{ V}$

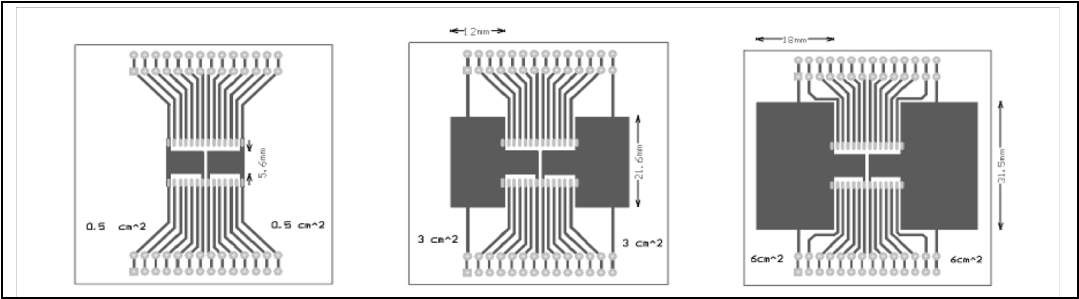
Values are generated with $R_L=0\Omega$

In case of repetitive pulses, T_{jstart} (at beginning of each demagnetization) of every pulse must not exceed the temperature specified above for curves B and C.

Figure 22. Demagnetization

4 SO-28 double island thermal data

Figure 23. SO-28 double island PC board



1. Layout condition of R_{th} and Z_{th} measurements (PCB FR4 area=58 mm x 58 mm, PCB thickness=2 mm, Cu thickness=35 μ m, Copper areas: 0.5 cm², 3 cm², 6 cm²)

Table 9. Thermal calculation according to the PCB heatsink area

Chip1	Chip2	T_{jchip1}	T_{jchip2}	Note
On	Off	$R_{thA} \times P_{dchip1} + T_{amb}$	$R_{thC} \times P_{dchip1} + T_{amb}$	
Off	On	$R_{thC} \times P_{dchip2} + T_{amb}$	$R_{thA} \times P_{dchip2} + T_{amb}$	
On	On	$R_{thB} \times (P_{dchip1} + P_{dchip2}) + T_{amb}$	$R_{thB} \times (P_{dchip1} + P_{dchip2}) + T_{amb}$	$P_{dchip1} = P_{dchip2}$
On	On	$(R_{thA} \times P_{dchip1}) + R_{thC} \times P_{dchip2} + T_{amb}$	$(R_{thA} \times P_{dchip2}) + R_{thC} \times P_{dchip1} + T_{amb}$	$P_{dchip1} \neq P_{dchip2}$

R_{thA} = Thermal resistance junction to ambient with one chip On
 R_{thB} = Thermal resistance junction to ambient with both chips On and $P_{dchip1}=P_{dchip2}$
 R_{thC} = Mutual thermal resistance

Figure 24. $R_{thj-amb}$ vs PCB copper area in open box free air condition

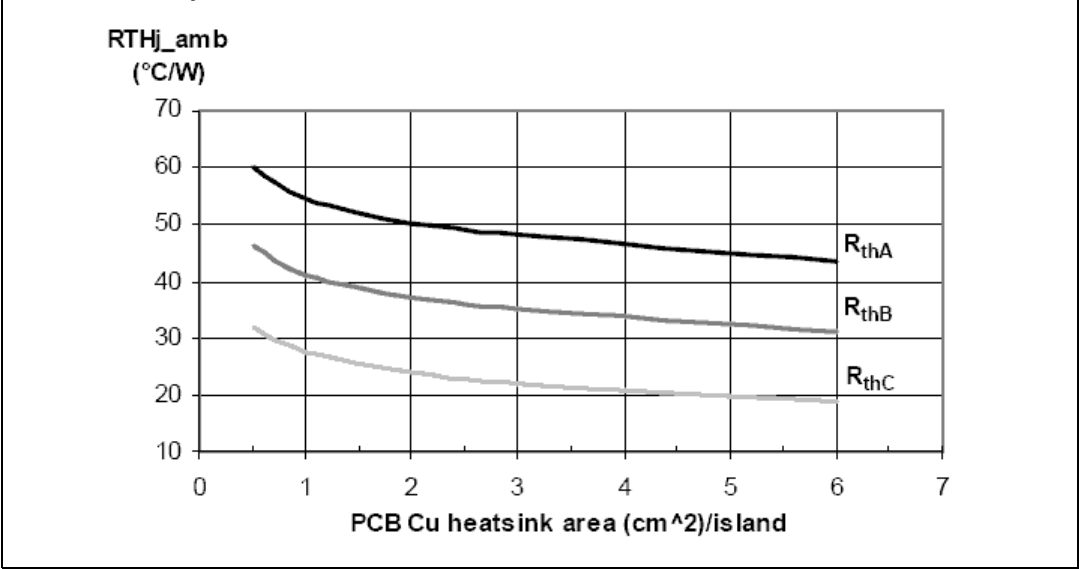


Figure 25. SO-28 thermal impedance junction ambient single pulse

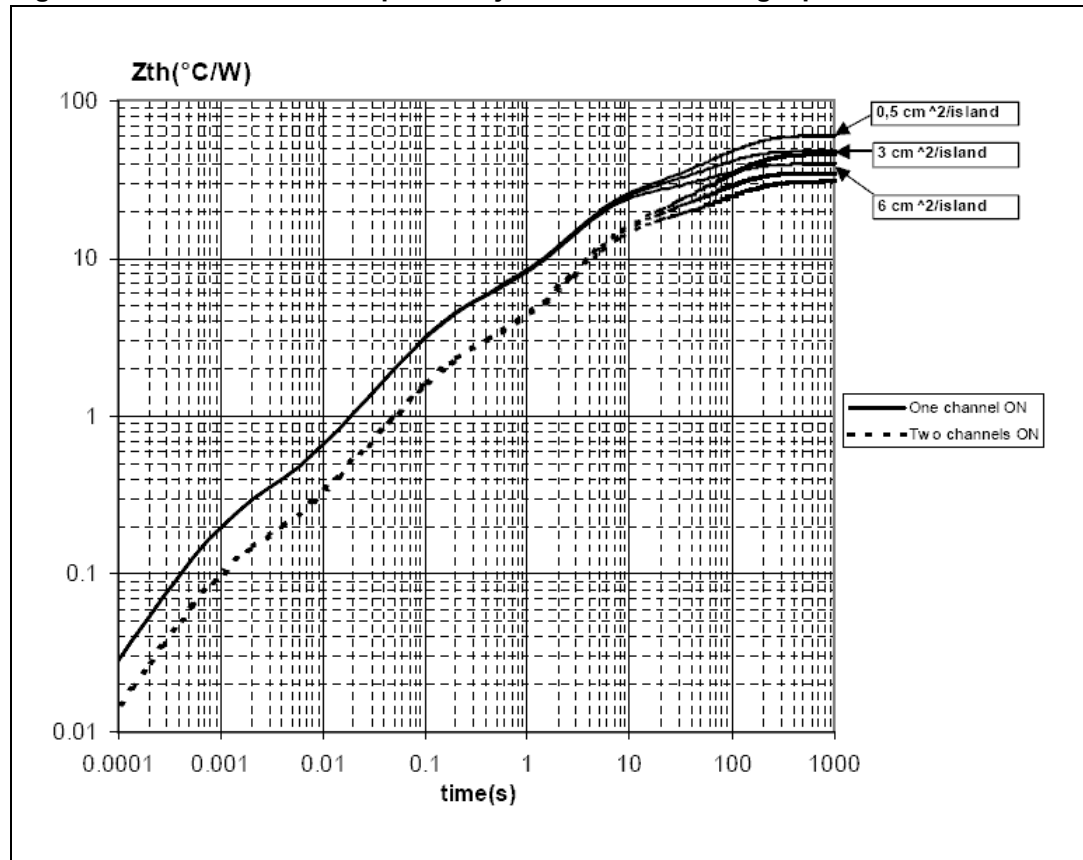
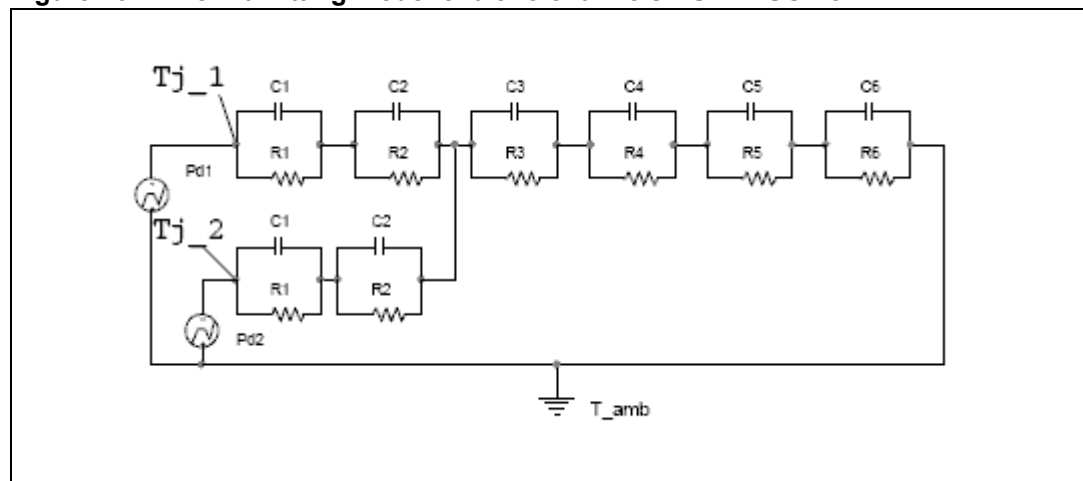


Figure 26. Thermal fitting model of a two channels HSD in SO-28



Pulse calculation formula

$$\delta = R_{TH} \cdot \delta + Z_{THtp}(1$$

where $\delta = t_p /$

Table 10. Thermal parameter

Area/island(cm ²)	0.5	6
R1=(°C/W)	0.02	
R2=(°C/W)	0.1	
R3=(°C/W)	2.2	
R4=(°C/W)	11	
R5=(°C/W)	15	
R6=(°C/W)	30	13
C1=(W.s/°C)	0.0015	
C2=(W.s/°C)	7.00E-03	
C3=(W.s/°C)	1.50E-02	
C4=(W.s/°C)	0.2	
C5=(W.s/°C)	1.5	
C6=(W.s/°C)	5	8

5 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com.

ECOPACK[®] is an ST trademark.

Figure 27. SO-28 mechanical data

DIM.	mm.			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			2.65			0.104
a1	0.10		0.30	0.004		0.012
b	0.35		0.49	0.013		0.019
b1	0.23		0.32	0.009		0.012
C		0.50			0.020	
c1	45 (typ.)					
D	17.7		18.1	0.697		0.713
E	10.00		10.65	0.393		0.419
e		1.27			0.050	
e3		16.51			0.650	
F	7.40		7.60	0.291		0.299
L	0.40		1.27	0.016		0.050
S	8 (max.)					

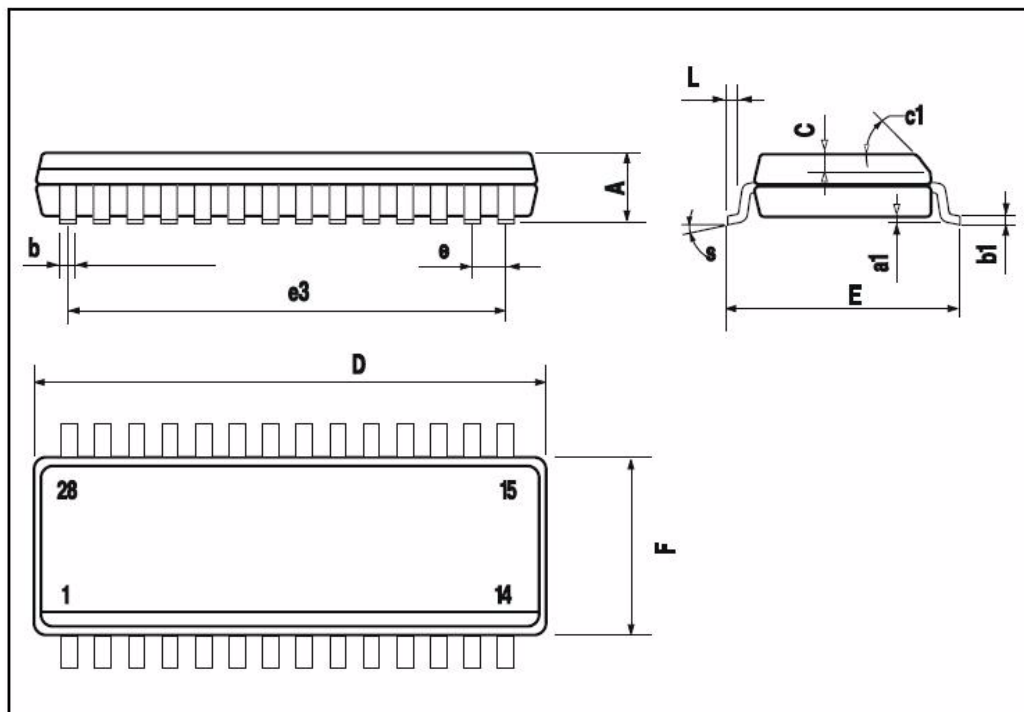


Figure 28. SO-28 tube shipment (no suffix)

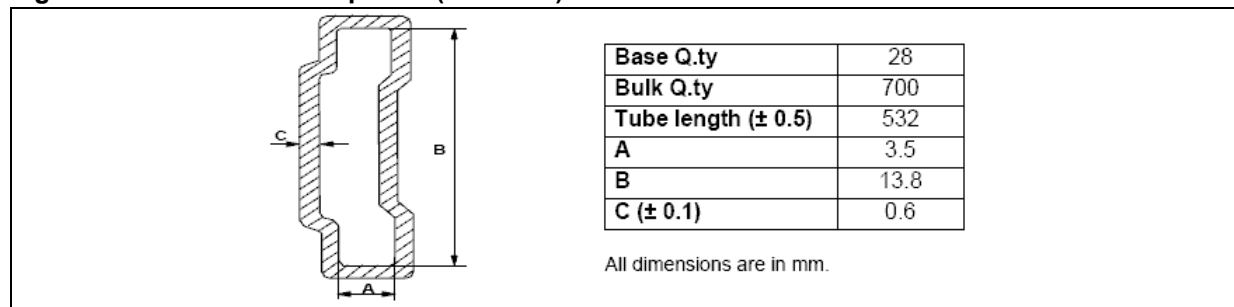
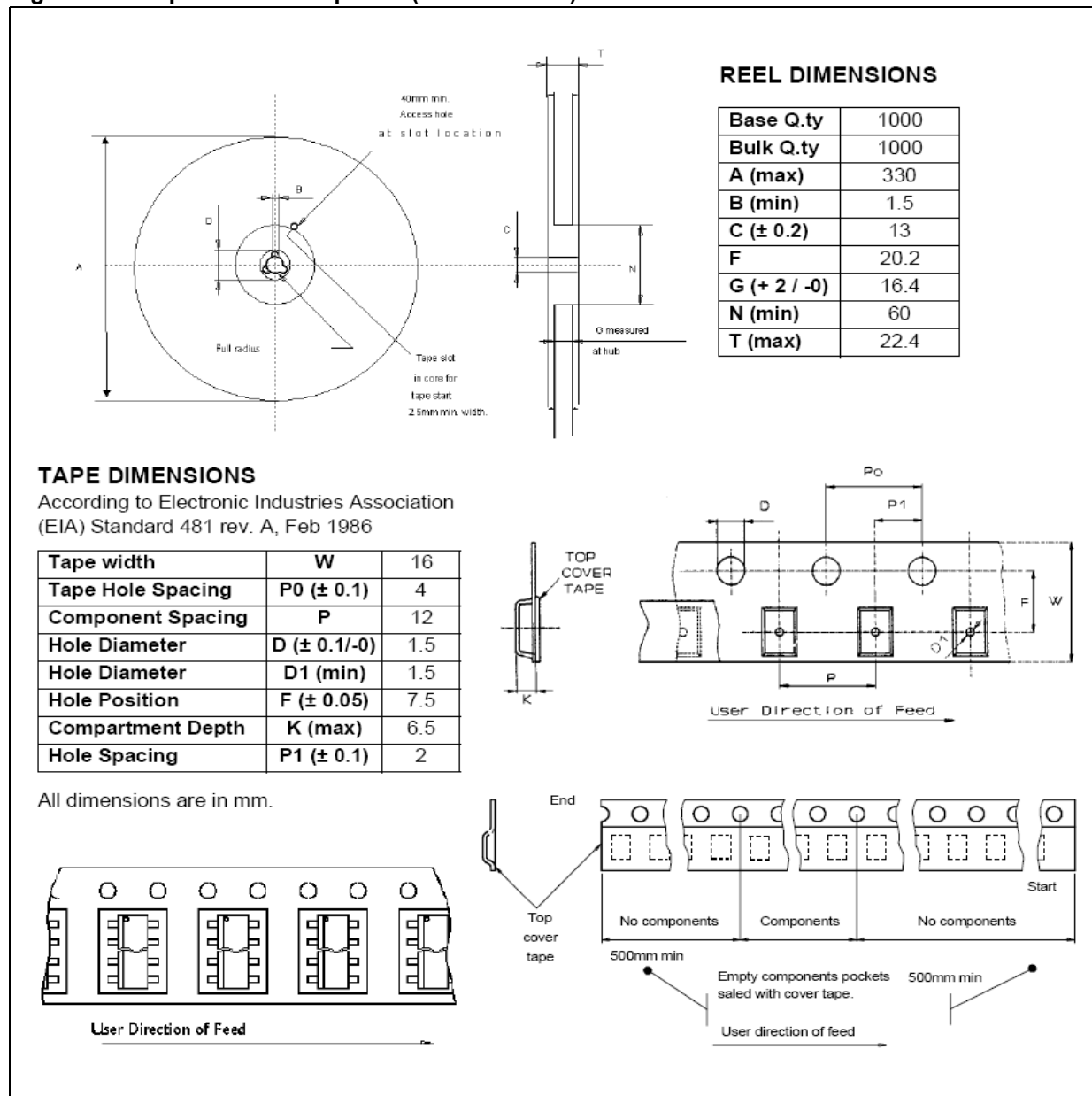


Figure 29. Tape and reel shipment (suffix "13TR")



6 Revision history

Table 11. Document revision history

Date	Revision	Changes
05-Mar-2006	1	Initial release.
16-Apr-2009	2	Document reformatted. Added Table 1: Device summary on page 1 . Updated Section 5: Package information on page 24

Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY AN AUTHORIZED ST REPRESENTATIVE, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2009 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com